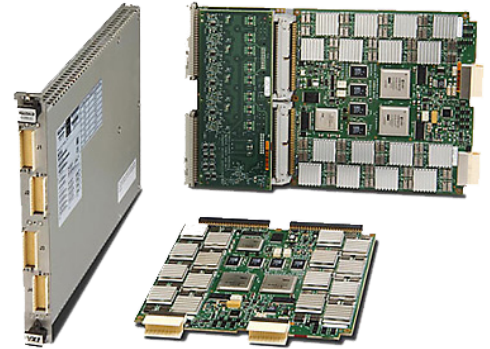


ScanWorks® Teradyne Di-Series Integration Software

Overview

Teradyne's Di-Series hardware is the industry's most advanced family of digital test instruments. Di-Series hardware instruments support 64 (single-ended) or 32 (differential-pair) programmable channels per card, data rates up to 50 MHz, and the flexibility, performance and ease of use to test all levels of integration from SRA/SRU to WRA/LRU.



Seamless Integration

Because ASSET's ScanWorks Boundary-Scan Test software support the Di-Series hardware, board test and programming operations developed for the ScanWorks environment can be executed on Di-Series VXI hardware instruments configured in a Teradyne test system like a Spectrum 9100 or LM Star.

Test and Programming

The test vectors generated by ScanWorks are applied through the high-speed digital channels of a Di-Series VXI instrument by accessing the IEEE 1149.1 test access port (TAP) on the unit under test (UUT).

The Di-Series instrument also provides other means for accessing the digital I/O on the UUT. The Di-Series instrument functions as a ScanWorks controller. As such, it is well suited for IEEE 1149.1 and IEEE 1149.6 interconnect test, memory test, and PLD/FPGA or NOR/NAND flash programming. Testing cluster devices and other areas on the UUT can be accomplished effectively with the ScanWorks Component Action, macro programming language and scripting language, all of which are supported on Di-Series instruments.

Powerful Debugging

The debugging capabilities with Di-Series instruments are as powerful as those supported by all ScanWorks controllers. From the ScanWorks action debug tool, actions can be run step-by-step in real time, and reads and writes can be performed to any register, pin, or bus on the UUT.

ScanWorks Platform for Embedded Instruments

ScanWorks Platform for Embedded Instruments is a seamless software environment to access, run and collect data from any instrument in your chips, circuit boards or systems. The ScanWorks Platform includes products for Boundary-Scan Test (BST), Processor-Controlled Test (PCT), FPGA-based Fast Programming (FFP), FPGA-Controlled Test (FCT) and IJTAG test.

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